



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION

Generic Copy

30-SEP-2005

SUBJECT: ON Semiconductor Final Product/Process Change Notification #15025

TITLE: Assembly Transfer of PDIP Packages from OSE-P to AIT

EFFECTIVE DATE: 30-Nov-2005

AFFECTED CHANGE CATEGORY(S): Subcontractor Assembly Site

AFFECTED PRODUCT DIVISION(S): Analog Power Management

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or Bob Marquis <FC88FC@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office or William Fontes <FC8HYB@onsemi.com>

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Mohd Ibrahim A K B Maiden <FFN3DP@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 60 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

DESCRIPTION AND PURPOSE:

ON Semiconductor is pleased to announce plans to transfer assembly of 8, 14, 16, and 18 lead PDIP packaged parts from OSE-P to Advanced Interconnect Technology (AIT), located in Batam, Indonesia. The transfer is a manufacturing consolidation measure. AIT is QS9000, ISO9002, and TS16949 certified, and it has been a qualified assembly subcontractor for ON Semiconductor since 1990. AIT is qualified and currently assembling other Analog products for ON Semiconductor in 8, 14, 16, 18, 20, and 24 pin PDIP packages. In the case of Analog 14/16 lead PDIP products, AIT is the primary supplier for ON Semiconductor. The transferred devices will use AIT's standard Build of materials(BOM). Device parameters will continue to meet all Data Book specifications, and the reliability of the products will continue to meet or exceed ON Semiconductor standards.

**Final Product/Process Change Notification #15025****RELIABILITY DATA SUMMARY:**

The qualification testing was successfully performed (all tests passed) on the SCY994401P device type, a 16 Lead fused-frame PDIP packaged part. This device was selected as the qualification vehicle based upon its large size. Completed Reliability Tests are as follows:

Test Conditions Sample Size Duration

Op-life (HTOL) Biased at +125C 77 Units/lot 504 Hours

Temperature Cycle (TC) -65C to +150C 77 Units/lot 500 Cycles

Unbiased HAST (UHAST) +130C/85% RH 77 Units/lot 96 Hours

Autoclave (AC) +121C/100% RH/15 PSIG 77 Units/Lot 96 Hours

Wire Bond Pull Strength (BPS) After TC Test 30 Bonds/5 units

Solderability (SD) Steam age at +260C 15 Units/lot 8 Hours

Solderability (SD) Steam age at +310C 15 Units/lot 8 Hours

Physical Dimensions (PD) Per case outline 30 Units/lot

Note: The qualification testing entailed samples from 1 lot for the HTOL, SD, BPS, and PD evaluations and from 3 lots for the TC, UHAST, and AC tests.

There is also extensive generic reliability data already available within ON Semiconductor on the 8, 14 and 16 lead (Nonfused leadframes) PDIP packages assembled at AIT.

ELECTRICAL CHARACTERISTIC SUMMARY:

No measurable differences were observed at probe or final test.

The assembly change has no impact to device electrical performance.

CHANGED PART IDENTIFICATION:

No physical changes to the package outlines. Parts assembled at AIT can be identified by the "CP" factory code on the package.

AFFECTED DEVICE LIST**PART**

CS2841BEBN8

CS41014BN8

CS4121ENF16

CS44076N8

CS45092NF16

CS45134BN14

CS46054N8

CS5101EN14

CS68051NF16

CS68059NF16

CS68096NF16

CS69061N8

CS8151CGN8

CS8151YNF16

CS8190ENF16

CS92404BN16

CS93801N16

NCV7601P

SCV697601P

SCY994401P